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**NATIONAL STANDARD OF THE
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GB/T 17626.22-2017

**Electromagnetic compatibility (EMC) -- Testing and
measurement techniques -- Radiated emissions and immunity
measurements in fully anechoic rooms (FARs)**

(English Translation)

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References

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Definite degree

TABLE D.4 IMMUNITY TESTING FOR FREQUENCY RANGES OF 1 GHz TO 18 GHz IN FAR Uncertainty of Measurement Equipment and Facilities for Level Settings

Foreword

GB/T 17626 "Electromagnetic compatibility test and measurement technology" for the electromagnetic compatibility series of standards. Has released the national standards include.

GB/T 17626.1-2006 electromagnetic compatibility test and measurement techniques Immunity Test Summary;

GB/T 17626.2-2006 Electromagnetic compatibility testing and measurement techniques

Electrostatic discharge immunity test;

GB/T 17626.3-2016 Electromagnetic compatibility testing and measurement techniques RF electromagnetic field radiation immunity test;

GB/T 17626.4-2008 Electromagnetic Compatibility Testing and Measurement Technology; Electrical Fast Transient Burst Immunity Test;

GB/T 17626.5-2008 electromagnetic compatibility test and measurement techniques surge (impact) immunity test;

GB/T 17626.6-2008 Electromagnetic compatibility Testing and measurement techniques Immunity to conducted disturbances induced by radio frequency fields;

GB/T 17626.7-2017 Electromagnetic compatibility test and measurement technology Power supply systems and connected devices Harmonic, inter-harmonic wave measurement and Measuring instrument guide GB/T 17626.8-2006 Electromagnetic compatibility testing and measurement techniques Power frequency magnetic field immunity test;

GB/T 17626.9-2011 Electromagnetic compatibility test and measurement techniques pulsed magnetic field immunity test;

GB/T 17626.10-1998 Electromagnetic compatibility - Testing and measurement techniques; Damping magnetic field immunity test;

GB/T 17626.11-2008 electromagnetic compatibility test and measurement techniques voltage dips, short interruptions and voltage variations immunity test;

GB/T 17626.12-2013 Electromagnetic compatibility Testing and measurement techniques Ringing wave immunity test;

GB/T 17626.13-2006 Electromagnetic compatibility test and measurement technology AC power port harmonics, and power grid signal Low Frequency Immunity Test;

GB/T 17626.14-2005 Electromagnetic compatibility Testing and measurement techniques Voltage fluctuation immunity test;

GB/T 17626.15-2011 Electromagnetic compatibility testing and measurement techniques Scintillator function and design specifications;

GB/T 17626.16-2007 electromagnetic compatibility test and measurement techniques 0Hz ~ 150kHz common mode conducted disturbance immunity test;

GB/T 17626.17-2005 electromagnetic compatibility test and measurement techniques; DC power input port ripple immunity test;

GB/T 17626.18-2016 Electromagnetic compatibility Testing and measurement techniques Damped oscillatory wave immunity test;

GB/T 17626.20-2014 Electromagnetic compatibility test and measurement techniques

Transmitted electromagnetic waves (TEM) waveguides in the launch and immunity test;

GB/T 17626.21-2014 Electromagnetic compatibility test and measurement techniques;

GB/T 17626.24-2012 electromagnetic compatibility test and measurement techniques
HEMP conduction disturbance protection test methods;

GB/T 17626.27-2006 Electromagnetic compatibility testing and measurement techniques
Three-phase voltage unbalance immunity test;

GB/T 17626.28-2006 Electromagnetic compatibility Testing and measurement techniques
Power frequency variation Immunity test;

GB/T 17626.29-2006 Electromagnetic compatibility test and measurement techniques DC
power input port voltage sags, short interruptions and Voltage variation immunity test;

GB/T 17626.30-2012 electromagnetic compatibility test and measurement techniques of
power quality measurement methods;

GB/T 17626.34-2012 Electromagnetic compatibility test and measurement techniques
Mains supply voltage greater than 16A per phase current Dips, short interruptions and
voltage variations immunity tests.

This section GB/T 17626 Part 22.

This section drafted in accordance with GB/T 1.1-2009 given rules.

This section uses the translation method is equivalent to using IEC 61000-4-22:2010
"Electromagnetic Compatibility Part 4-22. Test and Measurement Technology Radiation
Emissions and Immunity Measurements in Anechoic Chamber (FAR) ".

This section made the following editorial changes.

--- In line with the existing standard series, the standard name was changed to
"electromagnetic compatibility test and measurement of radiation in the anechoic chamber
Launch and immunity measurement. " this part of the National Radio Interference
Standardization Technical Committee (SAC/TC79) and focal point.

This section drafted by the Ministry of Industry and Information Technology Electronics
Industry Standardization Institute, China Institute of Metrology, China Electric Power
Research Institute Institute, Shanghai Electric Apparatus Research Institute, Ministry of
Industry and Information Technology Fifth Institute, Southeast University, Space Group 203,
the National Radio Monitoring Center, Shaanxi Haitai Electronics Co., Ltd.

1 Scope

This section GB/T 17626 relates to the measurement of radiated emissions and radiated
immunity of electronic and/or electrical equipment, provides that the full electric wave Test
procedures for radiation emission and radiated immunity conducted in darkroom (FAR).